

Notice of References Cited

Application/Control No.

O9/771,986

Examiner

Yuwen Pan

Applicant(s)/Patent Under
Reexamination
LEE ET AL.

Art Unit
Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,115,592	09-2000	Ueda et al.	455/307
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NON-PATENT DOCUMENTS

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